

Attracting Tomorrow



Ceramic Capacitor Technology

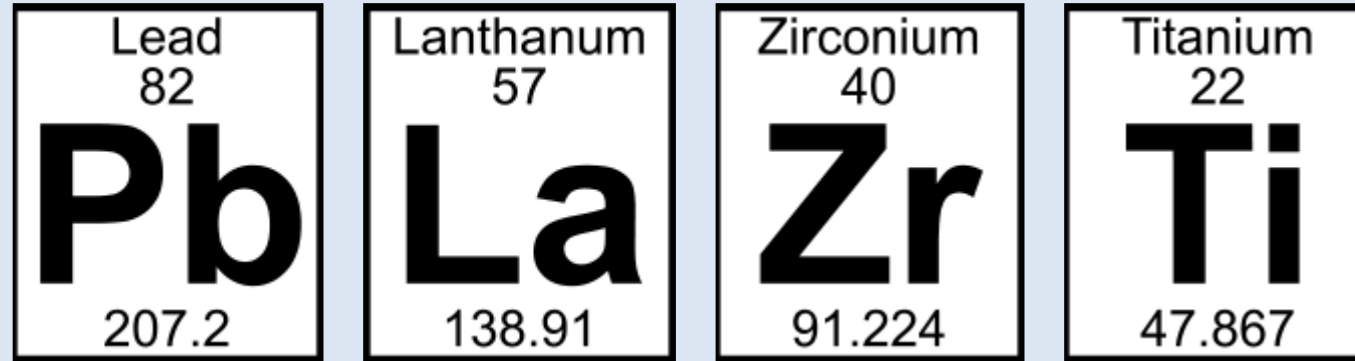
CeraLink™ Opens New Dimensions
in Power Electronics

EPCOS AG
A TDK Group Company
PPD Business Group
Germany
September 2018

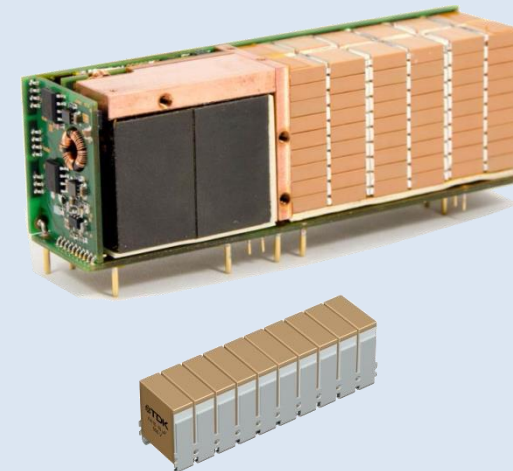
Ceramic Capacitor Technology



PLZT – a highly flexible ceramic material class

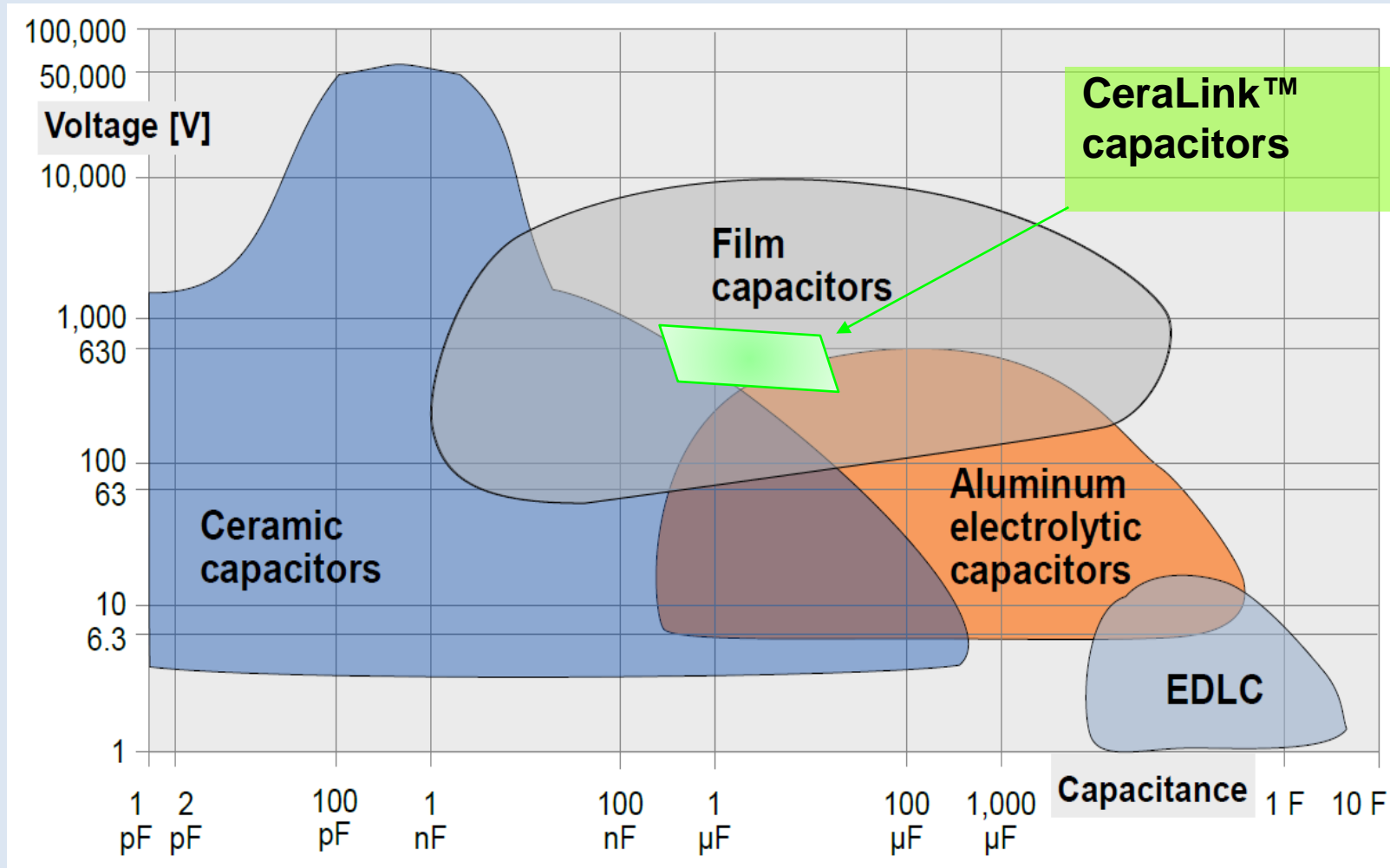


Piezo actuators

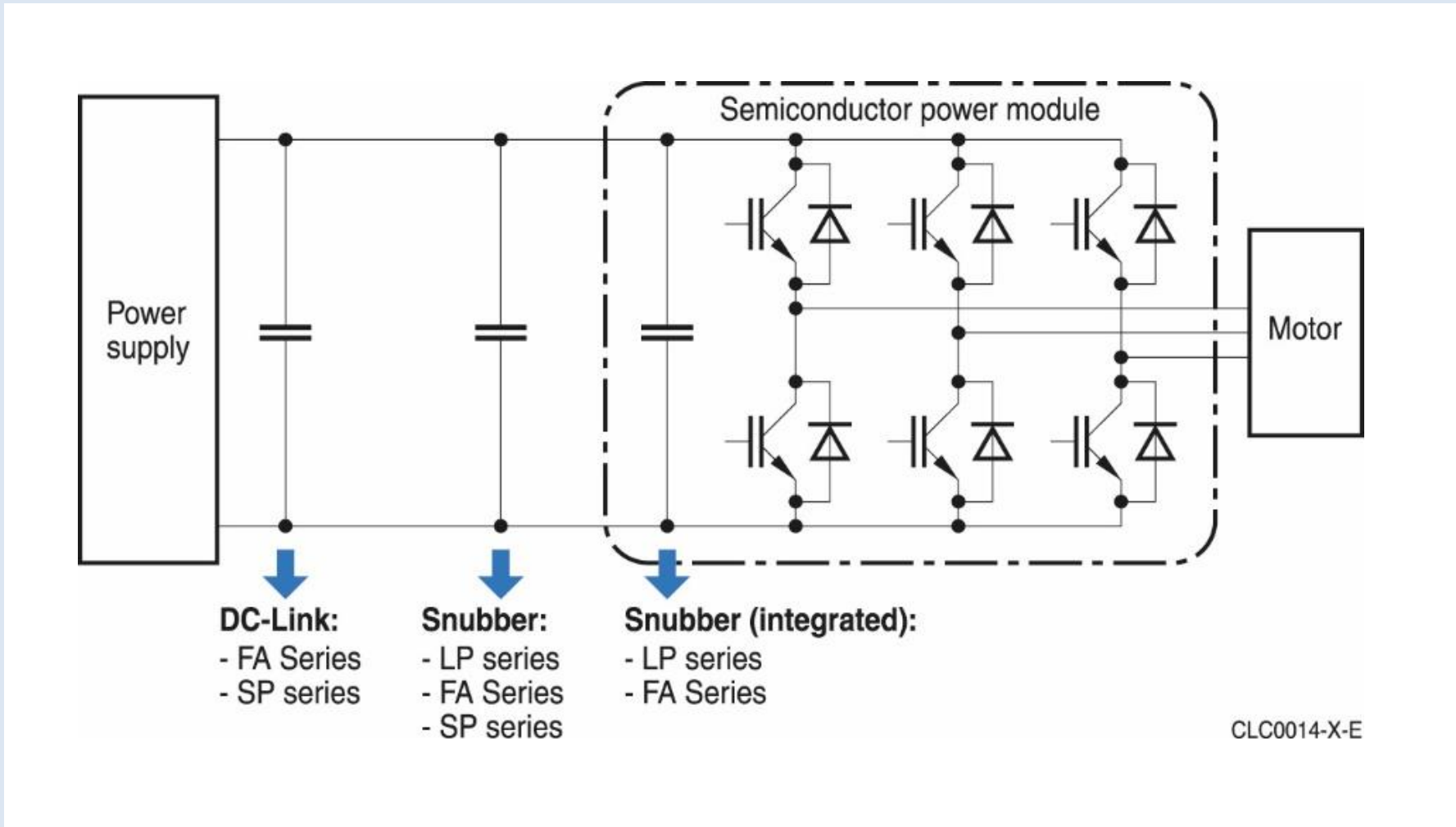


Capacitors

CeraLink™ at a first glance



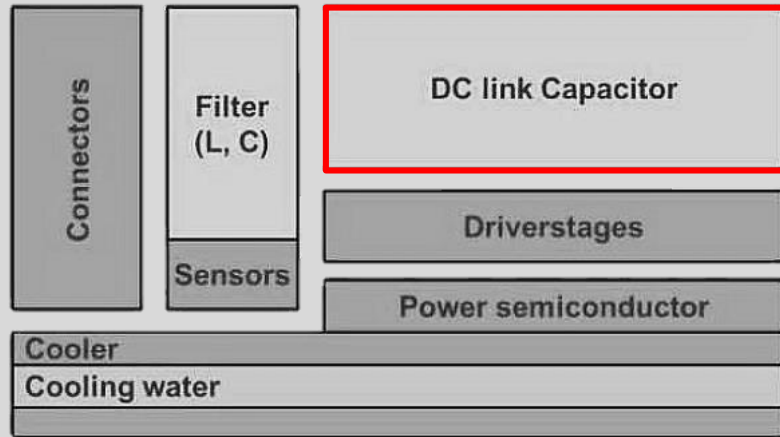
CeraLink™ at a first glance



CLC0014-X-E

New demands for DC link capacitors

Improvements in power density and efficiency were mainly driven by semiconductor technology in the last decade.



Example: principle block picture and size comparison of a motor inverter

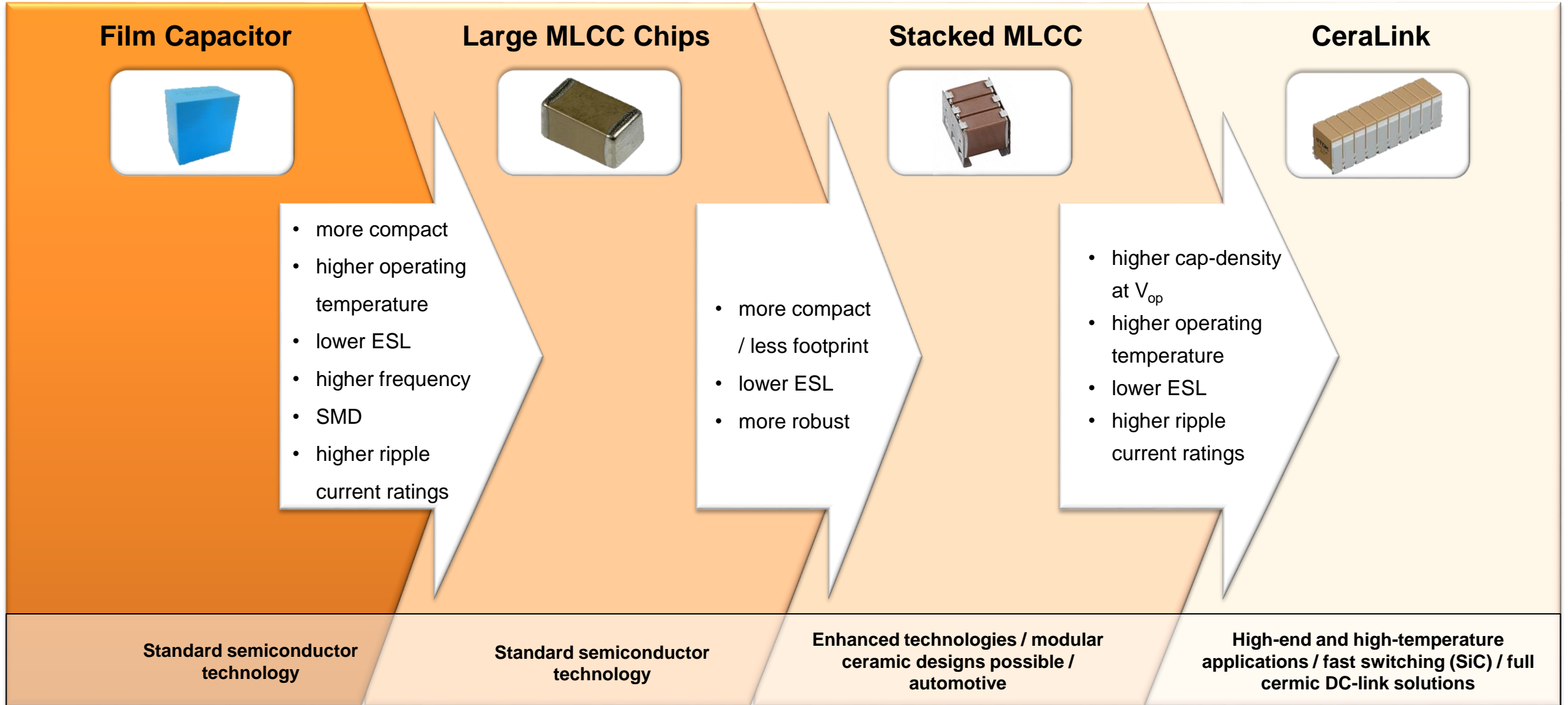
“Today the package of a motor inverter is mainly driven by the size of the capacitor, the bus bars, the terminal box and the filter components.”

Source: Plikat, Mertens, Koch, Volkswagen AG, Corporate Research, 2013

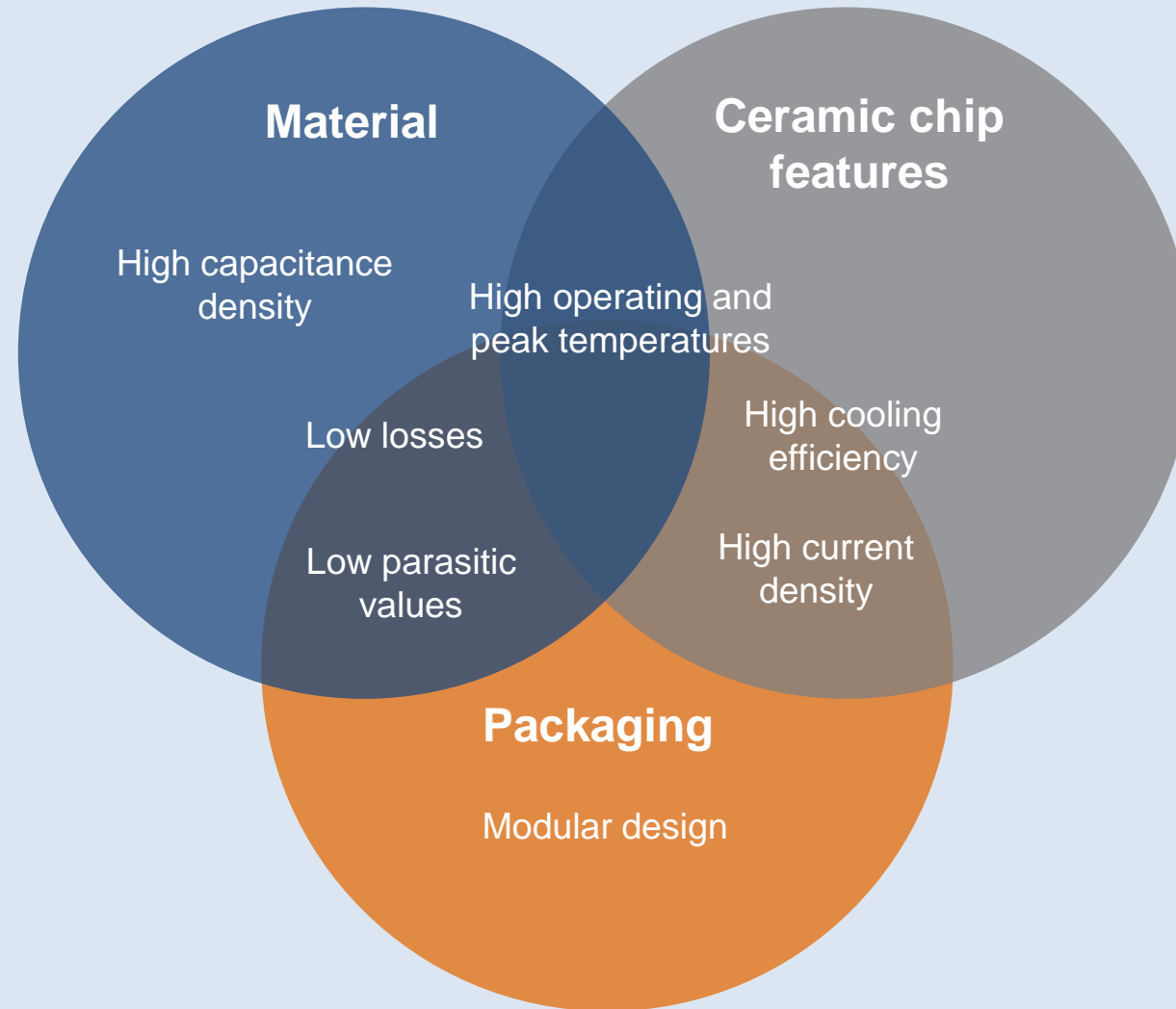
Requirements for a DC link capacitor

- High capacitance density
- High current density
- Low parasitic values (ESR/ESL) for fast switching
- Low losses in operation
- High operating and peak temperatures
- High cooling efficiency due to high thermal conductivity
- Support of distributed DC link capacitor topologies with low inductance components (modular design)

Technology guideline

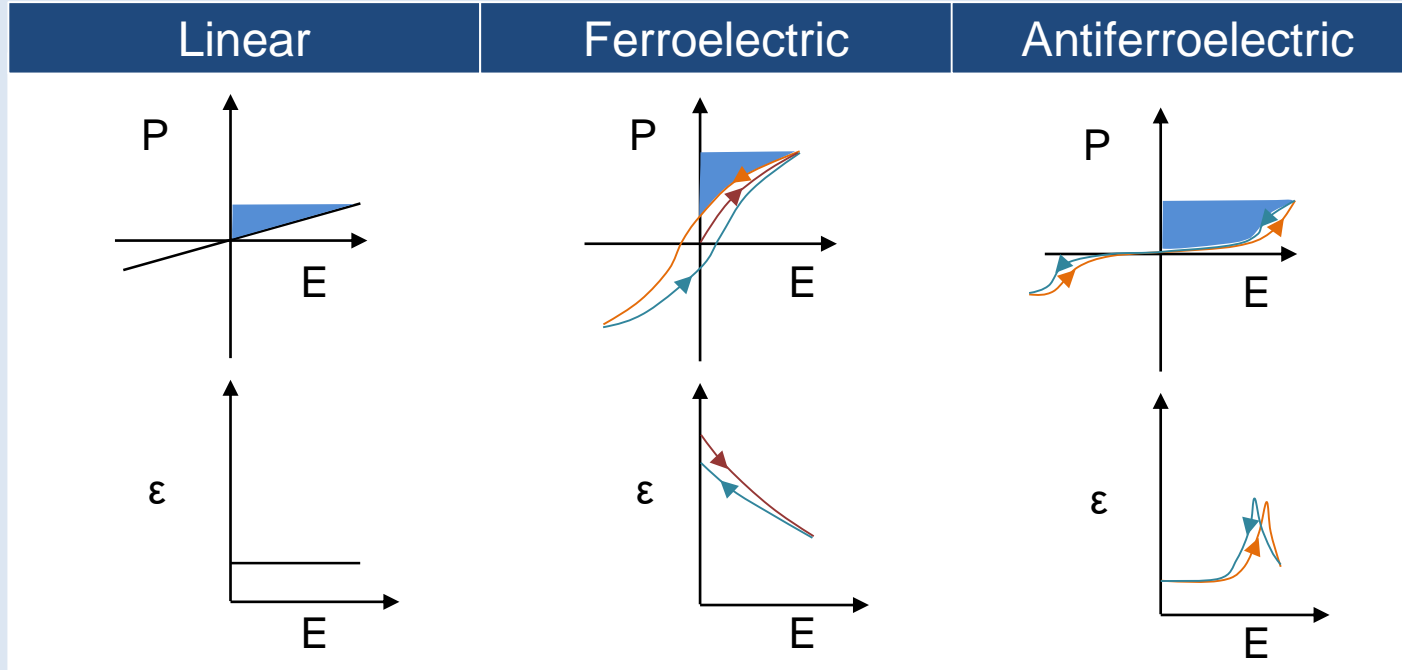


How does CeraLink™ meet these requirements?



Material

PLZT – an antiferroelectric material



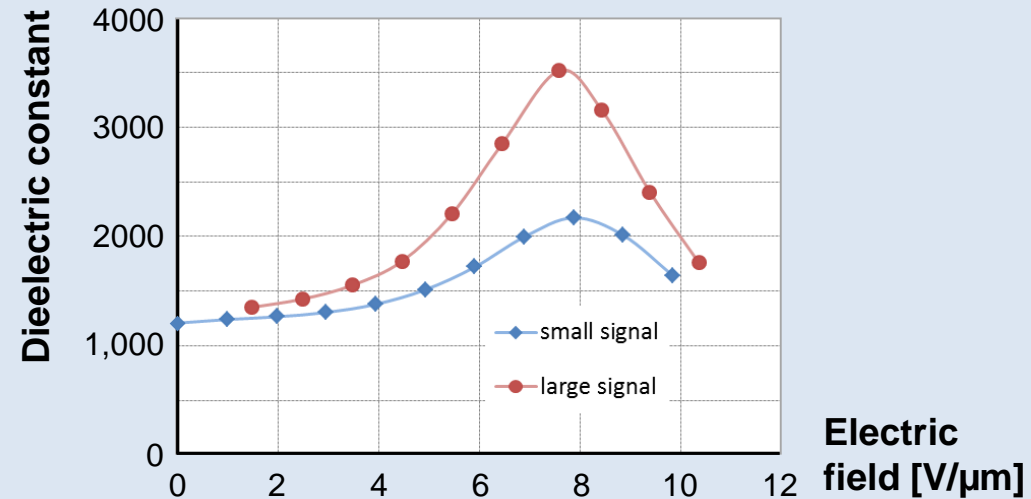
Nature of electrical polarization	Electronic, ionic	Permanent dipoles form ferroelectric domains	Permanent dipoles form antiparallel zones
Material class	(Ba,Nd)TiO, typ. NP0, C0G	BaTiO ₃ (BTO), typ. X7R	(Pb,La)(Zr,Ti)O ₃ (PLZT)
Advantages	ε constant over electric field and temperature	ε up to 10,000 is possible	ε increases with field
Disadvantages	ε < 100	ε decreases strongly with electrical field	ε low at zero bias

P Dielectric polarization
 E Electrical field strength
 ε Permittivity

High capacitance density at operating condition

- Due to antiferroelectric behavior, the characteristics of CeraLink™ are strongly non-linear and optimized for conditions under operation in power electronics
- Film capacitors and class 1 ceramics have a dielectric constant (nearly) independent on the electrical field. ($\epsilon < 100$)
- The permittivity of ferroelectric (e.g. X7R) MLCC capacitors is decreasing with electrical field
- CeraLink™ features an increasing dielectric constant up to the operating voltage
- At higher AC voltage (peaks), the material is able to provide even higher permittivities

DC bias characteristics at room temperature



	Film capacitor	Class 2 MLCC	CeraLink™
Nominal / rated capacitance	100 %	100 %	100 %
No bias voltage 0.5 V _{RMS}	100%	100 %	35 %
DC link voltage 0.5 V _{RMS}	100 %	35 %	60 %
DC link voltage 20 V _{RMS}	100 %	35 %	100 %

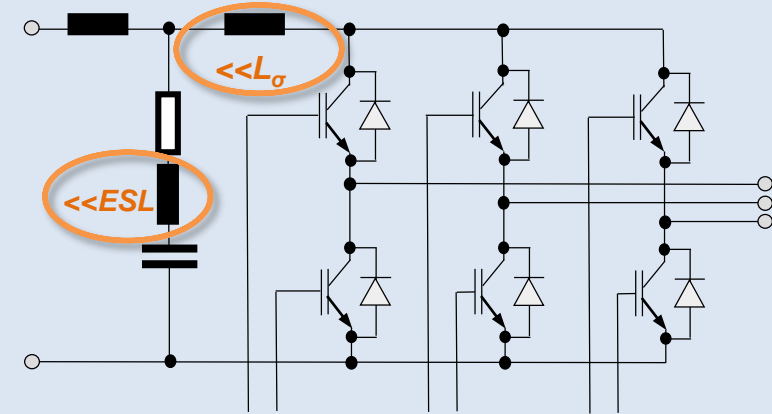
DC link (energy)

Snubber

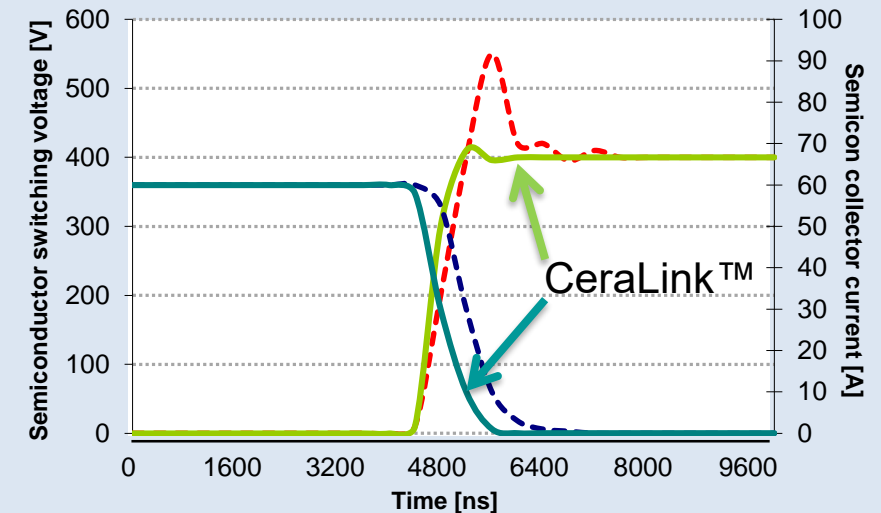
CeraLink™ is ideal for fast switching

Device characteristics lead to a low inductive commutation loop

- High capacitance density of 2 to 5 $\mu\text{F}/\text{cm}^3$
- **Low self-inductance (ESL) of 2.5 to 4 nH**
- High thermal robustness allows CeraLink™ to be placed very close to the semi-conductor with operation up to 150 °C permissible
- **No limitation of dV/dt**



Semiconductor overshoot principle



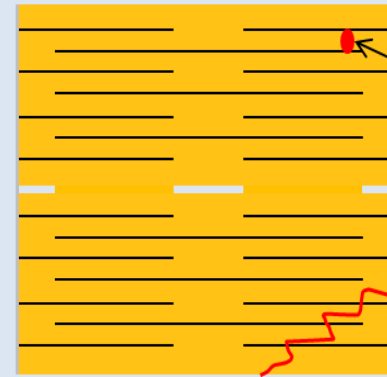
Ceramic Chip Features

Design for robustness against ceramic cracks

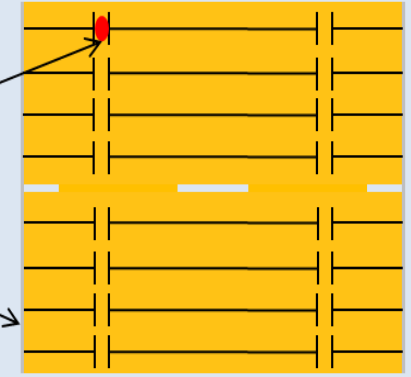
MLSC design

- Series connection of two MLCC geometries in one component.
- MLSC** design prevents short circuits caused by cracks from mechanical overstress

Multilayer series capacitor design



Equivalent circuit of series capacitances



arbitrary failure

outer electrode

MFD design

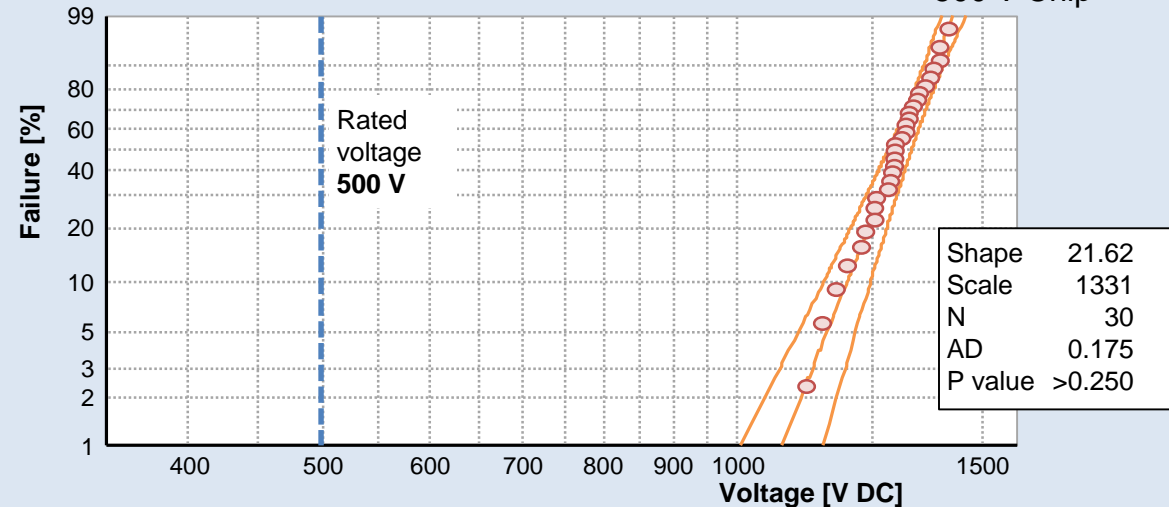
- Chip is segmented in height to reduce piezoelectric stress between active and inactive area



Breakdown voltage measurement

Weibull – 95% CI

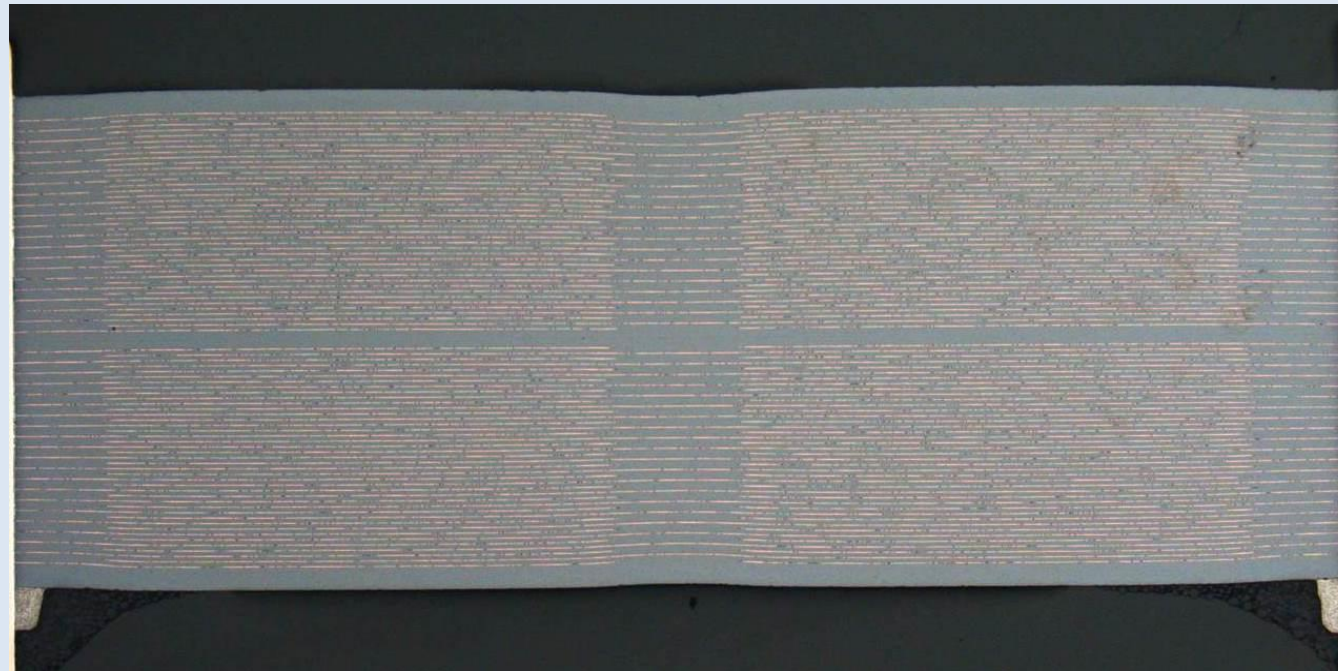
500 V Chip



Ceramic chip design for high current capability and high thermal conductivity

Copper inner electrodes

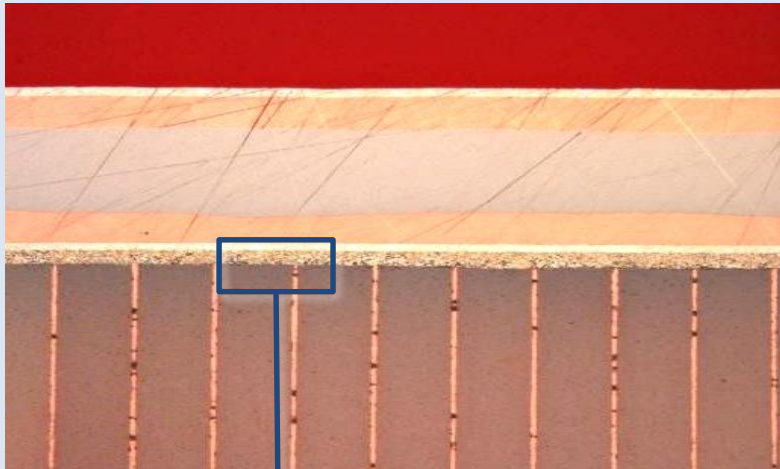
- Co-firing of PLZT ceramic material together with Cu is difficult, but possible
- Cu – process is one core competence of the piezo mother factory in Deutschlandsberg, Austria



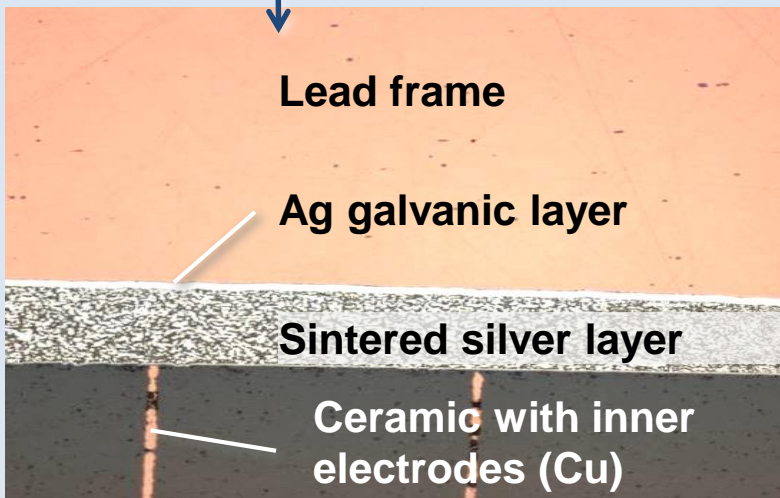
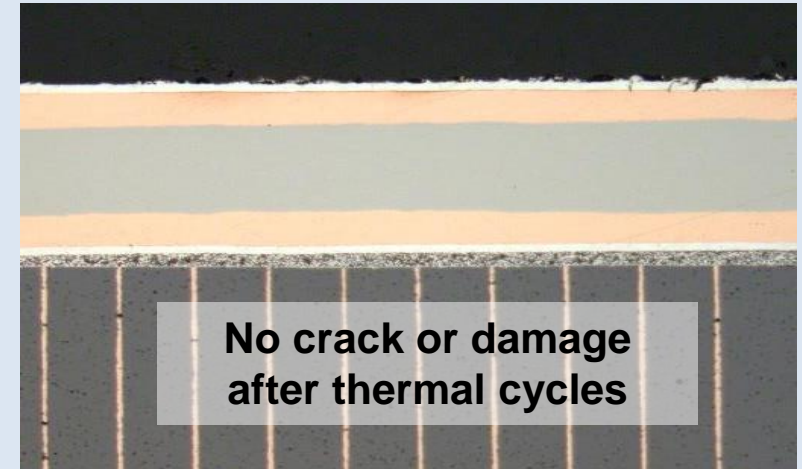
Cross section of the CeraLink™ multilayer chip consisting of appr. 80 dielectric ceramic layers

Packaging

Robust interconnection of metallic contacts



10,000 cycles thermal shock test (-55 °C to +150 °C)

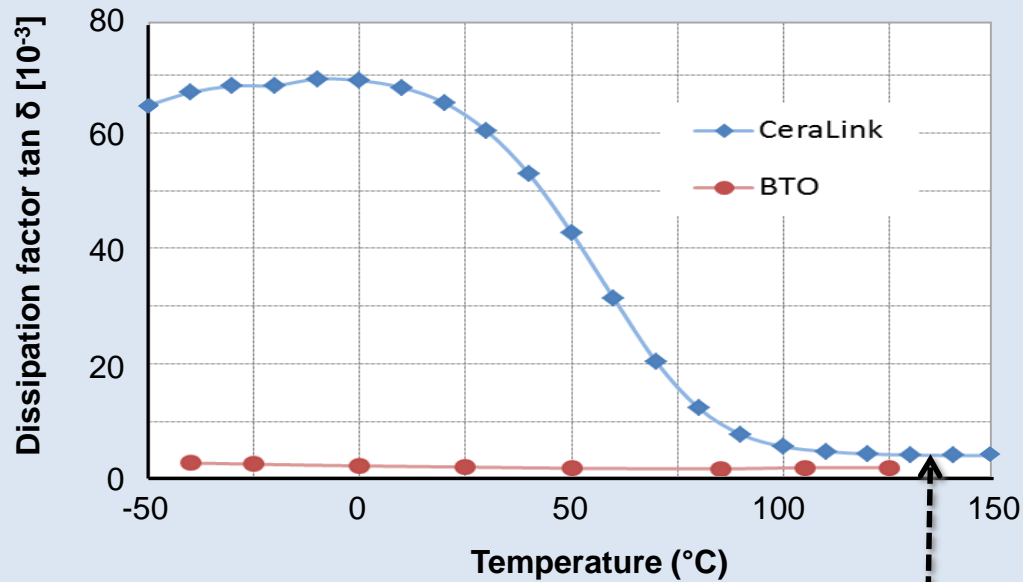


- Silver sinter connection between ceramic body and lead frame
- Outer contacts made of CIC (copper invar* copper), to combine high electrical and thermal conductivity with low coefficient of thermal expansion
- All materials are excellent thermal and electrical conductors (lowest thermal and electrical resistance)
- Silver layer prevents cracking of the ceramic in case of mechanical overstress or solder shock → open mode!

*Invar: 36Ni-Fe

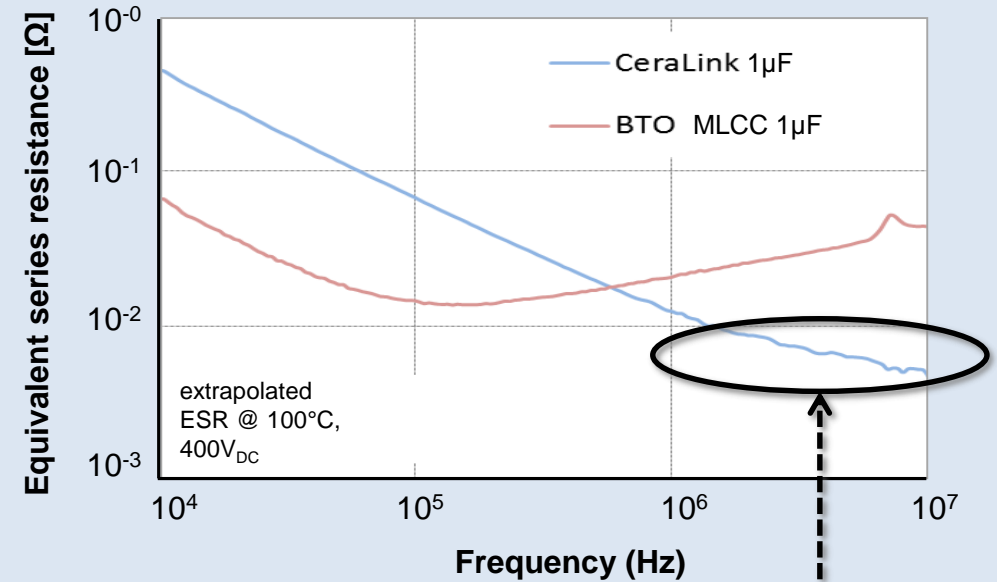
Low losses at high temperatures and frequencies

Comparison @ 1 V_{AC}, 1 kHz, 400 V_{DC}, 25 °C



Low dielectric loss at high temperatures

Comparison @ 0.1 V_{AC}, 0 V_{DC}, 25 °C



Minimal ESR due to low-loss copper electrodes and HF-suited backend

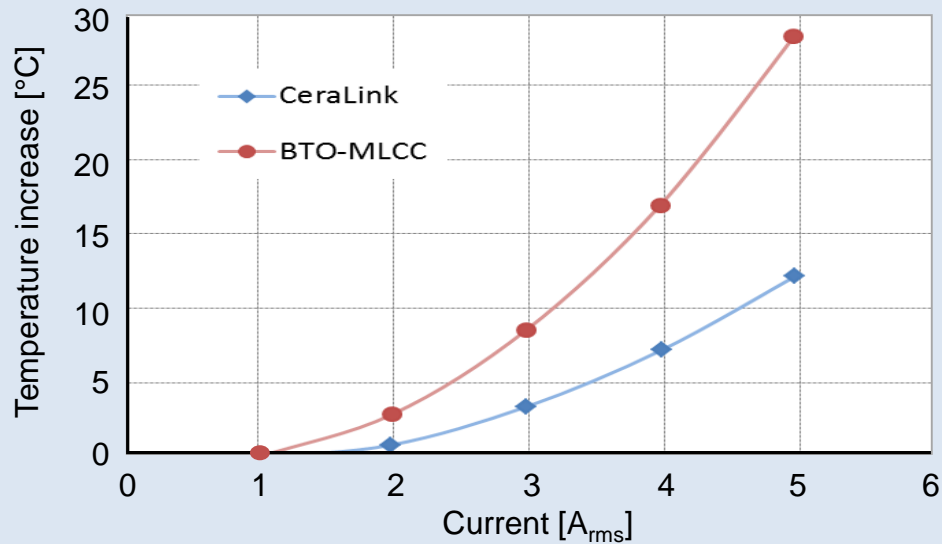
BTO = barium titanate oxide = standard MLCC material

Low self-heating and high current capability

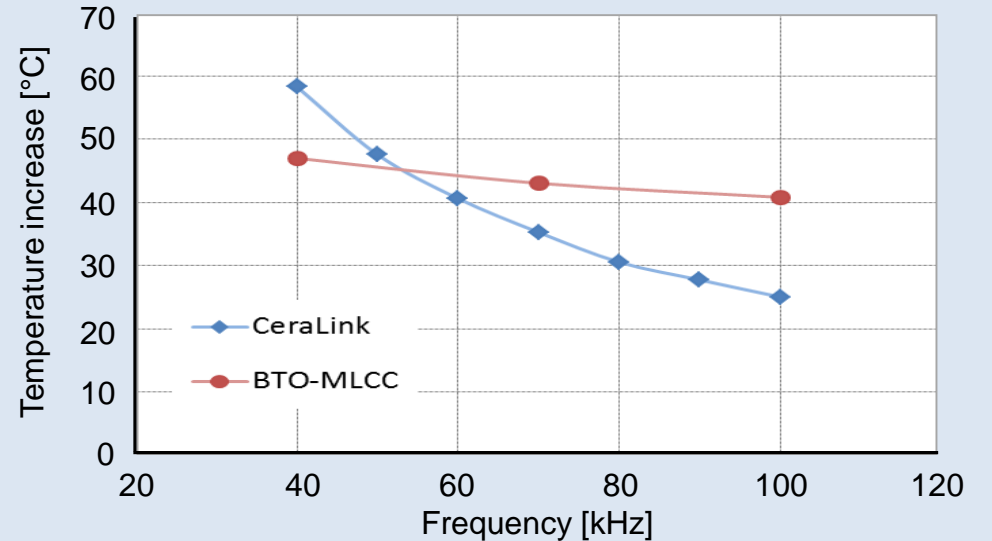
Due to low losses at high temperature and high frequency, CeraLink™ can carry more current under these conditions

Measurement condition	MKP film capacitor	BTO Class 2 MLCC	CeraLink™
Typical capacitance density @ DC link voltage, 20 V _{RMS} , 25°C	0.7 μF/cm ³	2.5 μF/cm ³	4.9 μF/cm³
Typical current rating per capacitance @ 100 kHz, 105°C	< 1 A/μF	< 4.5 A/μF	12 A/μF

Comparison @ 400 V_{DC}, 105 °C, 200 kHz



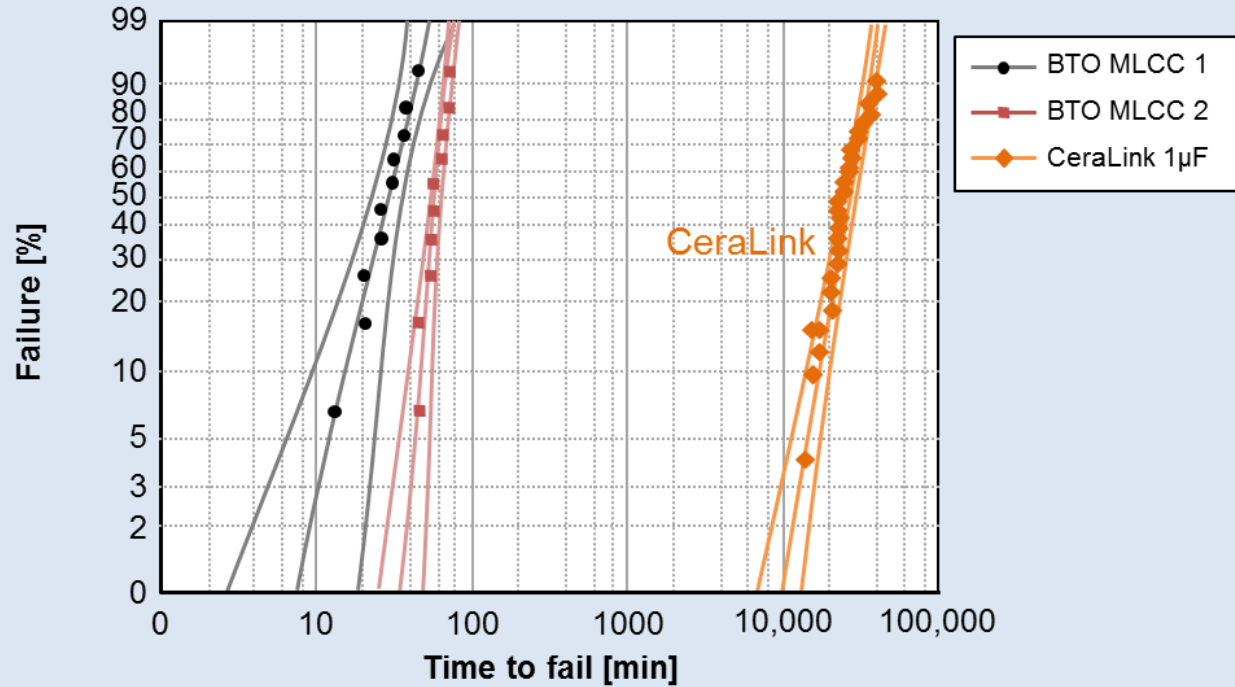
Comparison @ 400 V_{DC}, 85 °C, 5 A_{rms}



Measurements were carried out without active cooling (no forced air flow, no heat sink)

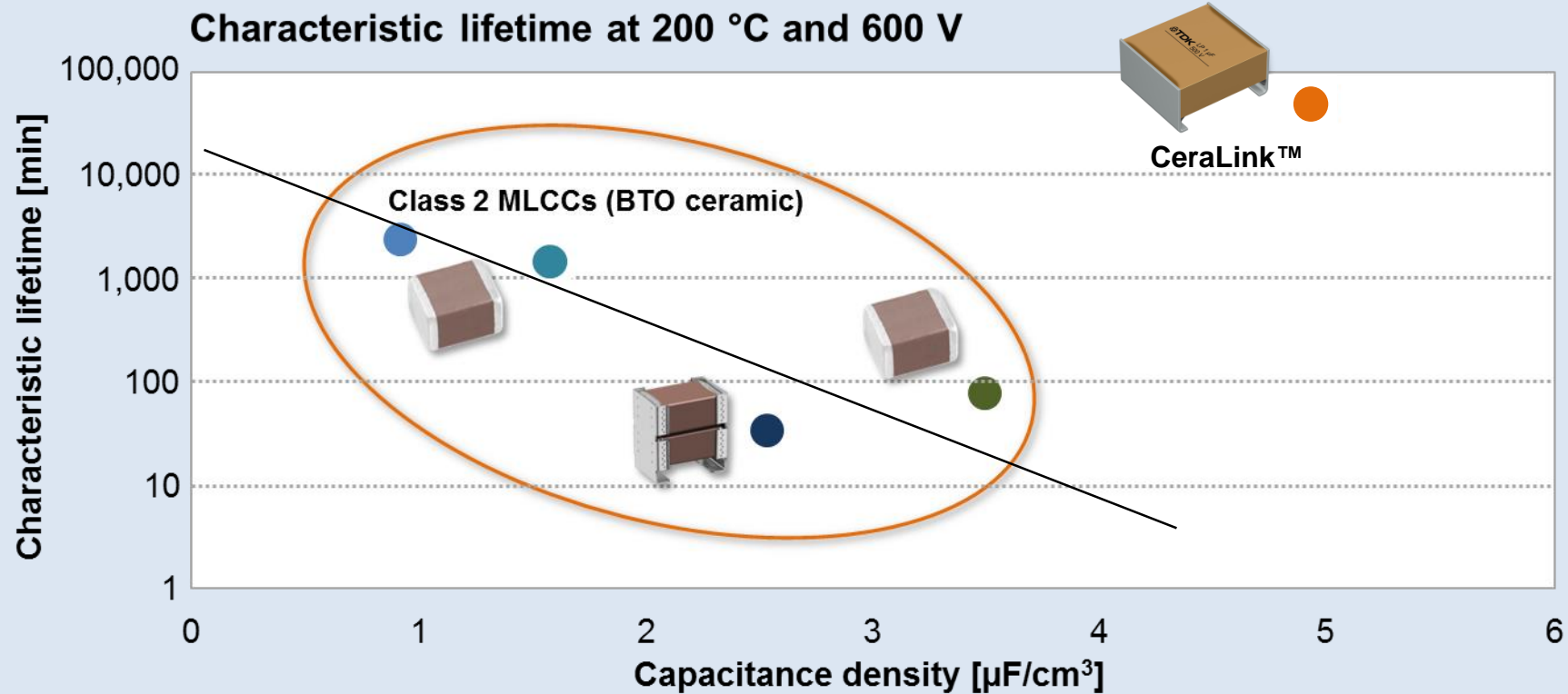
Exceptional lifetime at high temperatures

Highly Accelerated Life Test (HALT) 200 °C, 600 V DC
Weibull – 95% CI



Lifetime @ 200 °C three orders of magnitude higher than that of conventional ceramic capacitors

Lifetime at high temperatures – comparison of ceramic capacitors



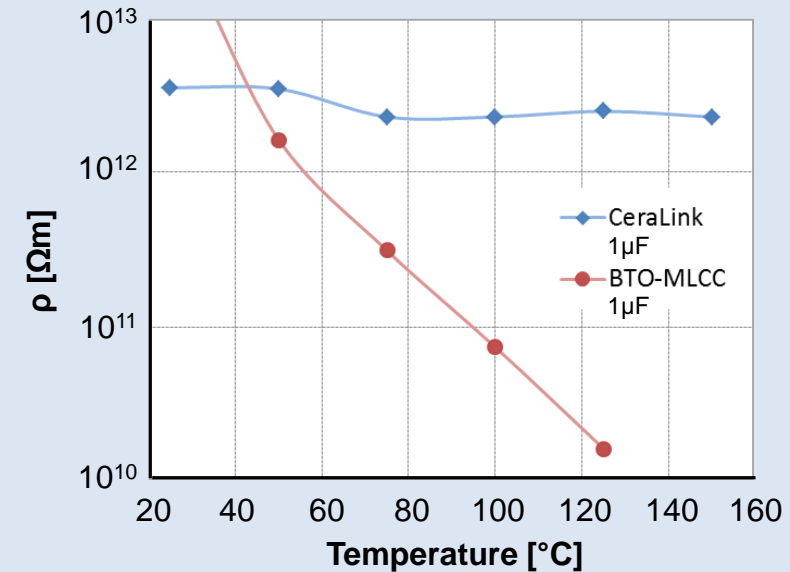
CeraLink™ offers highest lifetime and capacitance density compared to conventional ceramic capacitors

Low leakage current at high temperatures

CeraLink™ shows stable and outstanding high isolation properties compared to all existing capacitor technologies

- low leakage current at elevated temperatures even above 150°C
- No thermal runaway observed for CeraLink™ ceramic material

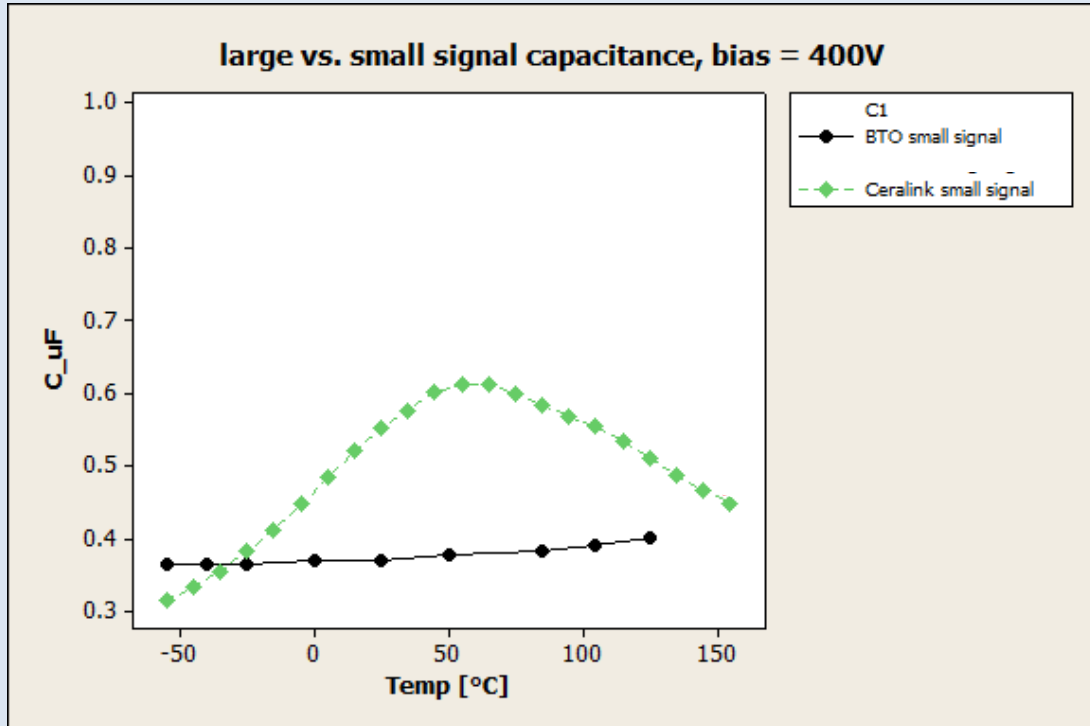
Comparison @ 400 V_{DC}



Parallel capacitors

No thermal runaway

The capacitance characteristic and low ESR of CeraLink™ avoid a thermal runaway:

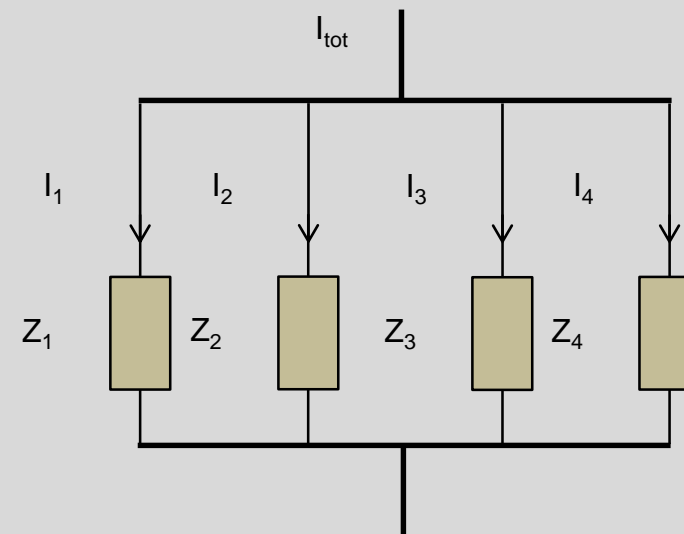


Green: CeraLink™ small signal capacitance measurement (0.1 V_{rms}, 1 kHz)

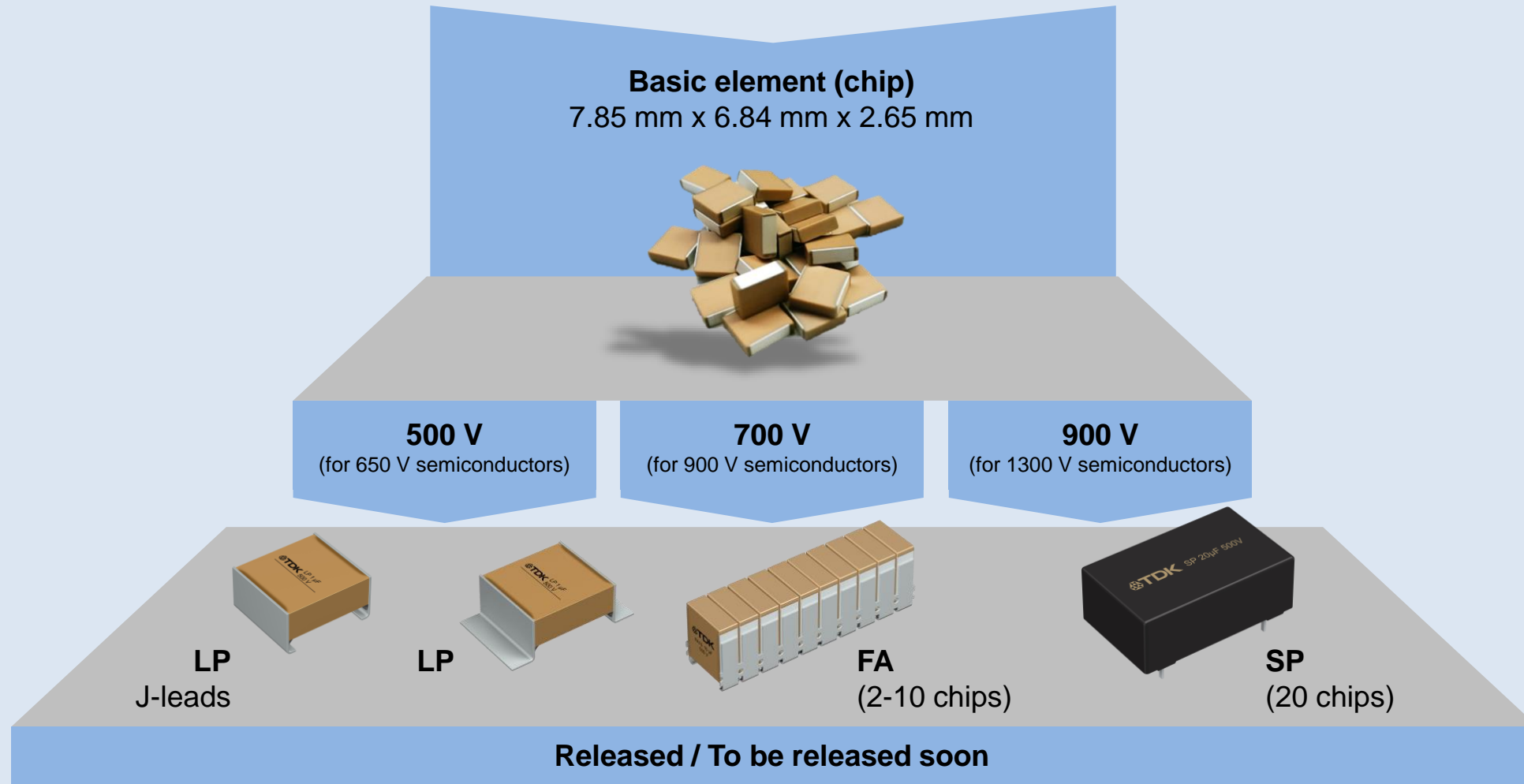
Black: TDK Megacap 1μF 630V → measurement (0.1 V_{rms}, 1 kHz)

Higher temperature leads to:


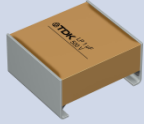
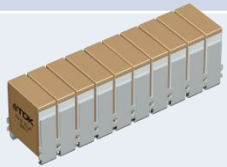

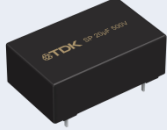
- Lower capacitance
- Higher impedance
- Lowest current through the **hottest** capacitor




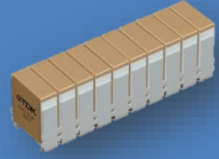
CeraLink™ Product portfolio – modular design



CeraLink™ product range

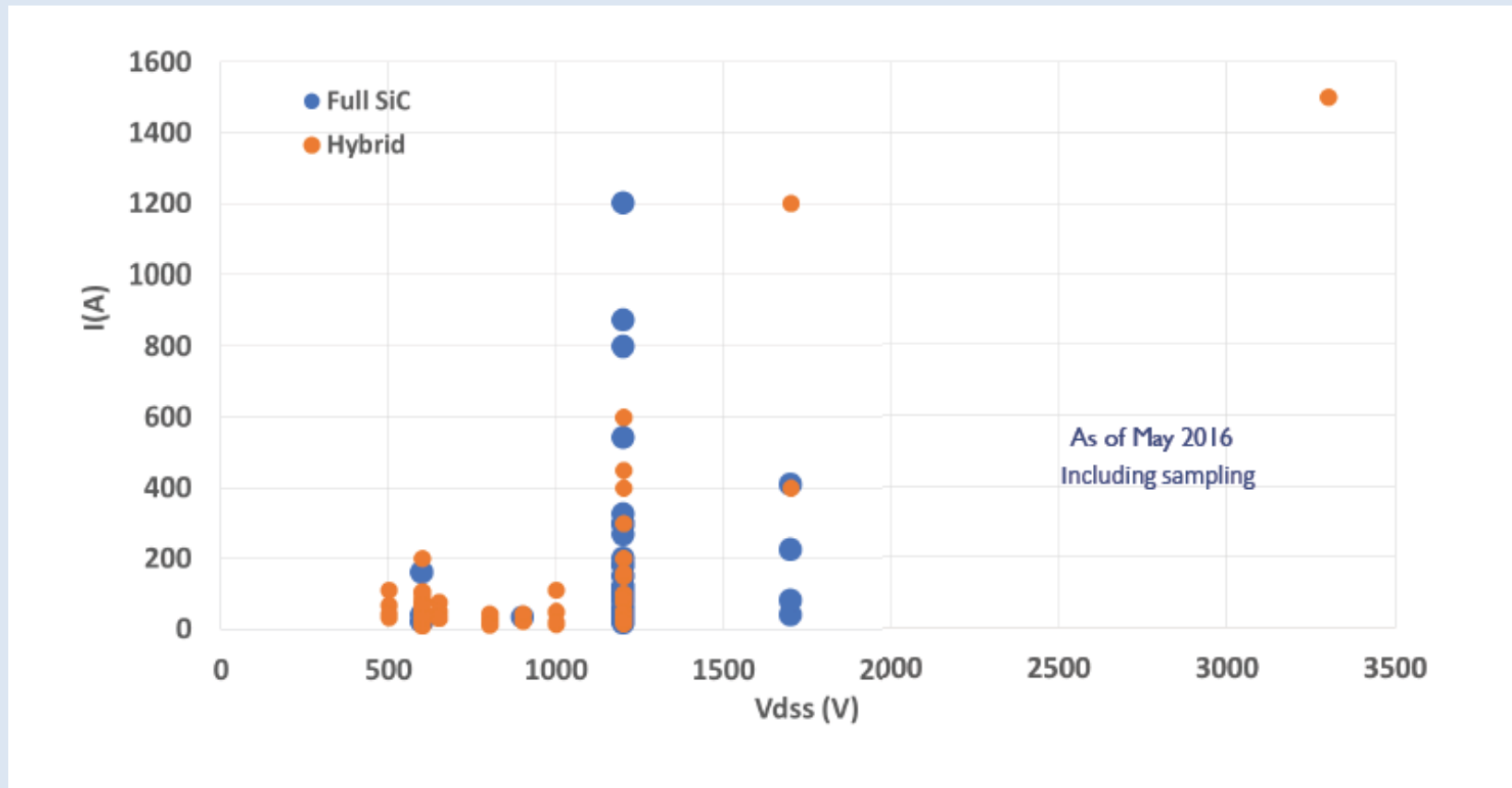
Series	Nominal capacitance / rated voltage		
Designed for	650 V semiconductors	900 V semiconductors	1300 V semiconductors
Low Profile LP (L leads) 	1 μ F / 500 V	0.5 μ F / 700 V	0.25 μ F / 900 V
Low Profile LP (J leads) 	1 μ F / 500 V	0.5 μ F / 700 V	0.25 μ F / 900 V
Flex Assembly FA10 	10 μ F / 500 V	5 μ F / 700 V	2.5 μ F / 900 V
Flex Assembly FA2 / FA3 	2/3 μ F / 500 V Release 09/18	1/1.5 μ F / 700 V Release 09/18	0.5/0.75 μ F / 900 V Release 09/18
Solder Pin SP 	20 μ F / 500 V	10 μ F / 700 V	5 μ F / 900 V

Comparison New FA10 vs. SP

	Solder Pin (SP) 	Flex Assembly (FA10) 	
Ceramic chip	PLZT ceramic, MLSC design, copper inner electrodes, sputter layer	PLZT ceramic, MLSC design, copper inner electrodes, sputter layer	~
Number of ceramic chips	20	10	
Lead frame	Cu meander structure / solder pin	CIC (copper-invar-copper) multilayer material, J-shaped connectors for each chip; SMD mounting technology	+
Voltage rating	500 / 700 / 900 V	500 / 700 / 900 V	~
Nominal capacitance	5 μ F (900 V) – 20 μ F (500 V)	2.5 μ F (900 V) - 10 μ F (500 V)	~
Current rating (f = 100 kHz; VDC = U _{op} ; T _{ambient} = 85°C)	24 A _{rms} (1.2 A _{rms} per chip; 900 V type)	32 A _{rms} (3.2 A _{rms} per chip; 900 V type)	+
Mounting area	726 mm ² (square area; 36 mm ² per chip)	213 mm ² (21.3 mm ² per chip)	+
Zhermomechanical stability	-50 / 150°C / 1000 cycles no damage, no degradation	-55 / 150 °C / 1.000 cycles no damage, no degradation -55 / 150 °C / 10.000 cycles tested on the package system w.o. damage	+
Weight per chip	1.55 g	1.15 g	+

SiC market

Availability of various voltage classes



Source: Littlefuse white paper

1200 V SiC power modules → Ideal for our 900 V series

Application example - Industry

Integrated servo drive

Traditional design



Integrated servo drive

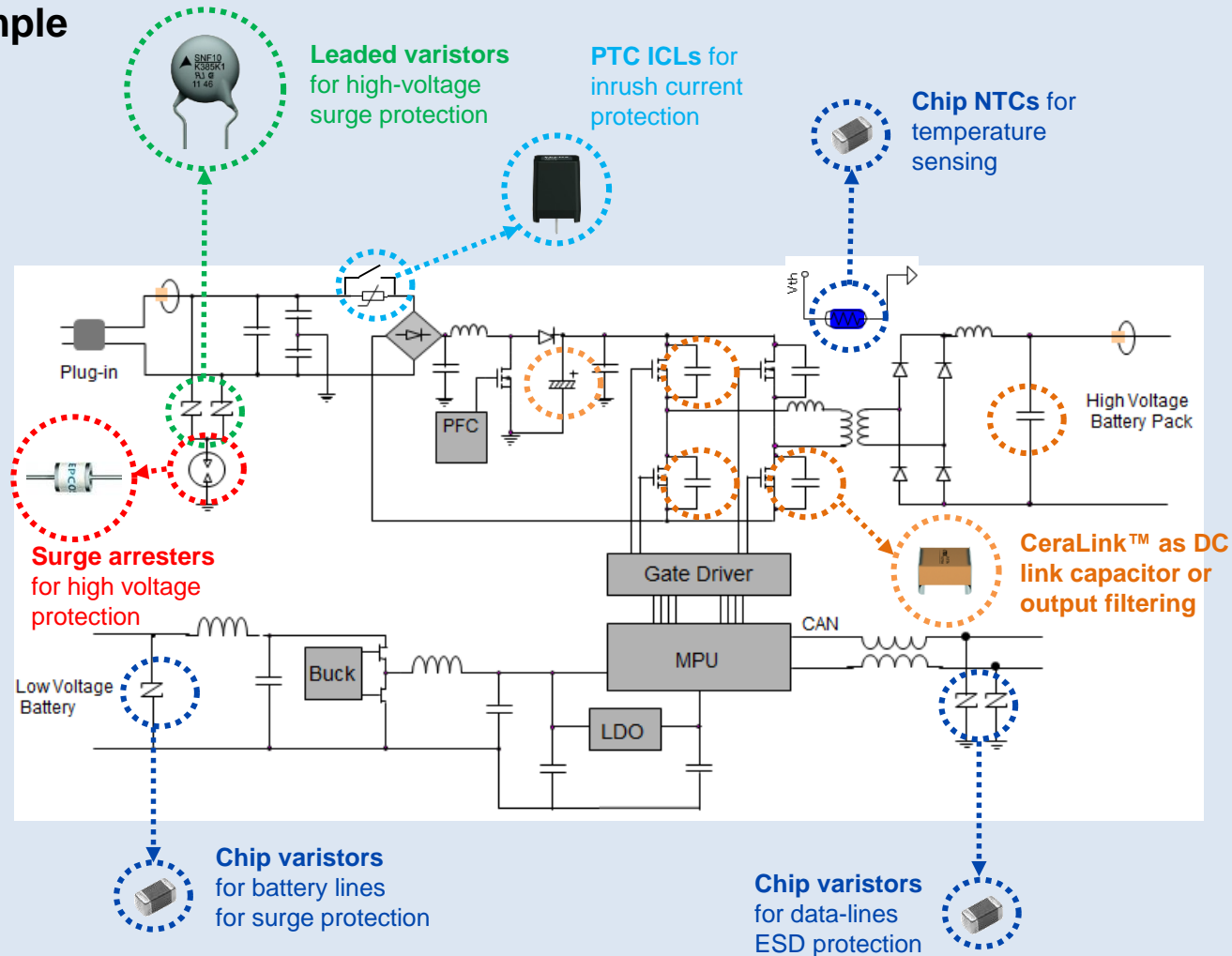
- ... electronics is integrated into the motor housing
- ... SiC for new designs

Temperature

Low ESL

Application example - Automotive Onboard chargers

Example



Recommended products (selection)

- Chip NTCs (thermal sensing against overheating)**
 - B57232V5103+360
 - B57332V5103+360
 - NTCG164LH104H
- Chip varistors (ESD protection for data lines)**
 - CT0402S17AG
 - CT0603L25HSG
 - AVR1608C270MT*
- Chip varistors (low voltage surge protection)**
 - CT0805S14BAUTOG
 - CT1206S14BAUTOG
 - CT2220K30G
 - AVR2012C390KT6AB
- Leaded varistors (high voltage surge protection)**
 - SNF14K***E2K1
 - SNF20K***E2K1
- Surge arresters (high voltage protection)**
 - EHV6*-H...B1-B7
 - EHV60-H...SMD
- PTC ICLs (inrush current protection)**
 - J21x series
- CeraLink™ (DC link capacitor or output filtering)**
 - B58031*
 - Flex Assembly FA2 or FA3

Application examples

Ideal for demanding applications

Motor sports



Power supplies for medical equipment



Test & measurement



Electric aircraft



Down-hole power supplies (gas & oil)



Traction (SiC)



Temperature

Robust Design

Low weight
Small size

Outlook: Chip CeraLink™ 2220 in development

	TDK MLCC Height: 2.5 mm	CeraLink™ 2220 Height: 1.4 mm	
Capacitance @ 0 V DC, 25 °C	470 nF	60 nF	✘
Capacitance @ 400 V DC, 25 °C	183 nF	110 nF	✘
Capacitance @ 400 V DC, large signal, 25 °C	183 nF	220 nF	✓
Size [l x w x h]	5.7 x 5 x 2.5 mm	5.6 x 4.7 x 1.4 mm	✓
Capacitance density @ 400 V DC (400 V DC large signal)	2.57 μF/cm ³	3.4 (6.6) μF/cm ³	✓
T_{max}	125 °C	150 °C	✓
I_{rms} @ 100 kHz*	2.1 A _{RMS}	4.0 A _{RMS}	✓

* T_{amb} = 85°C / f = 100 kHz / VDC = 400V / calculated from I_{rms} = 3 A and device temperature after 15 min

Target:
CeraLink™ 2220
2220 200 nF 500 V
Standard termination



Benchmark MLCC:
C5750X7T2J474K250KC
2220 470 nF 630 V
Standard termination

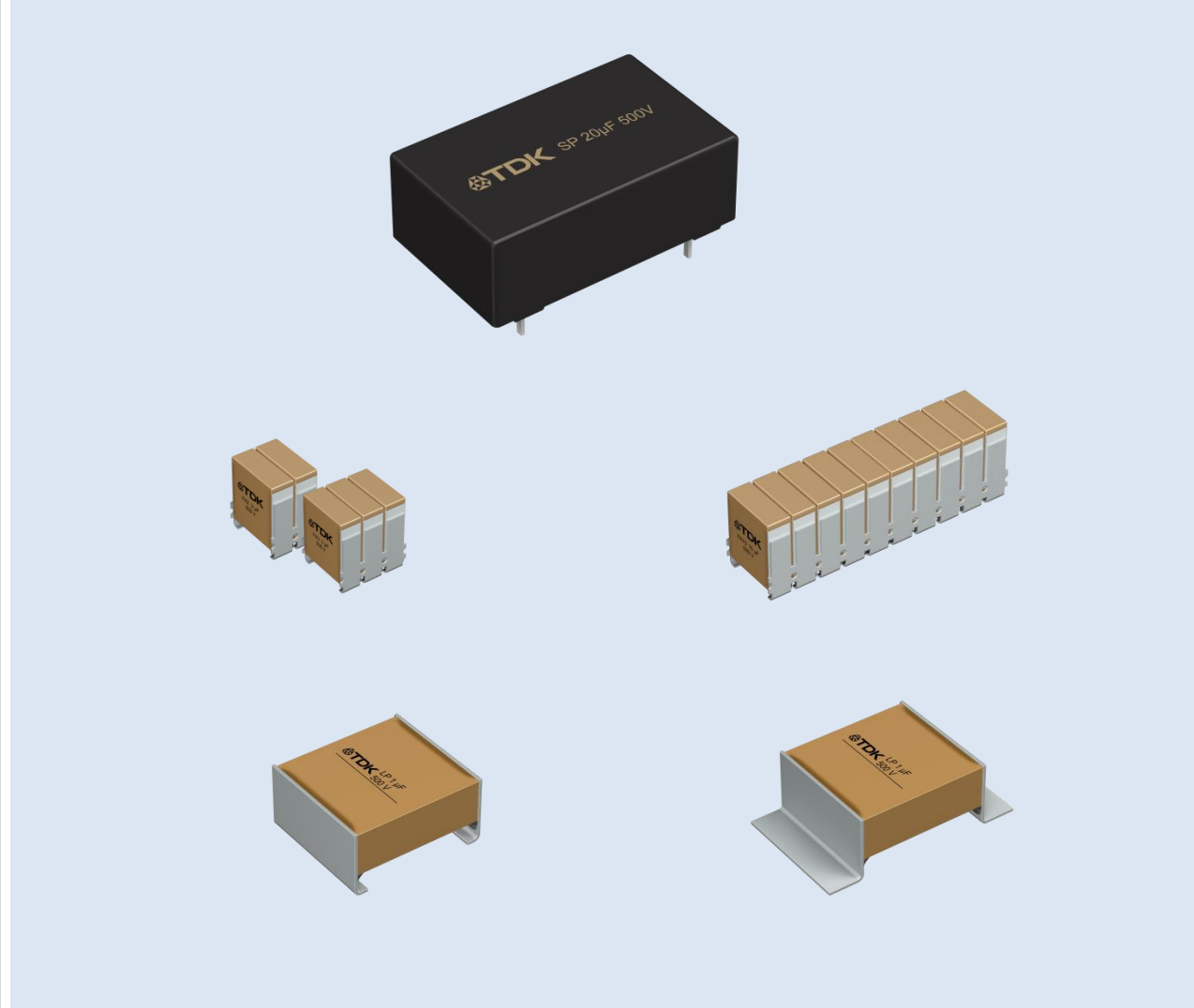


- Optimized for capacitance density (MLCC design)
- No stress-relief layer necessary for 1 mm active packet (1.4 mm chip height)
- Termination: Cu cap with Ni/Sn galvanics

Summary

Key benefits of CeraLink™

- Effective capacitance increases with rising voltage and leads to **high capacitance density**
- **Low ESL** and low inductive connection
- **Low ESR** especially at high frequencies and high temperatures
- **High current density**
- **High operating and peak temperatures** with temperature excursions up to 150°C
- **High robustness against high temperatures**
- Supports **fast-switching semiconductors** and high switching frequencies
- Supports further **miniaturization** of power electronics at the system level





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